

L Number	Hits	Search Text	DB	Time stamp
1	13	((((scanning adj electron adj microscope and secondary adj electron) and magnification) and rate near3 scan\$6) and (sweep\$5 swept))	USPAT; EPO; JPO; DERWENT	2004/07/09 08:52
2	46	((scanning adj electron adj microscope and secondary adj electron) and magnification) and (beam with (sweep\$5 swept))	USPAT; EPO; JPO; DERWENT	2004/07/09 08:53
-	7581	detect\$4 and magnification and frequency and image	USPAT; EPO; JPO; DERWENT	2003/04/08 08:56
-	325	(detect\$4 and magnification and frequency and image) and first adj scan\$5 and second adj scan\$5	USPAT; EPO; JPO; DERWENT	2003/04/08 08:57
-	39	((detect\$4 and magnification and frequency and image) and first adj scan\$5 and second adj scan\$5) and 250/\$.ccls.	USPAT; EPO; JPO; DERWENT	2003/04/08 09:25
-	6	((((detect\$4 and magnification and frequency and image) and first adj scan\$5 and second adj scan\$5) and 250/\$.ccls.) and scanning adj electron adj microscope	USPAT; EPO; JPO; DERWENT	2003/04/08 09:25
-	2	((detect\$4 and magnification and frequency and image) and first adj magnification and second adj magnification) and 250/\$.ccls.	USPAT; EPO; JPO; DERWENT	2003/04/08 09:12
-	1227	(detect\$4 and magnification and frequency and image) and 250/\$.ccls.	USPAT; EPO; JPO; DERWENT	2003/04/08 09:25
-	110	((detect\$4 and magnification and frequency and image) and 250/\$.ccls.) and scanning adj electron adj microscope	USPAT; EPO; JPO; DERWENT	2003/04/08 09:31
-	0	variable adj scan\$5 adj range and fixed adj scan\$5 adj range	USPAT; EPO; JPO; DERWENT	2003/04/08 09:48
-	61	((((detect\$4 and magnification and frequency and image) and 250/\$.ccls.) and scanning adj electron adj microscope) and secondary adj electron	USPAT; EPO; JPO; DERWENT	2003/04/08 09:48
-	42	(detect\$4 and magnification and frequency and image) and first adj magnification and second adj magnification	USPAT; EPO; JPO; DERWENT	2003/04/09 11:31
-	2039	scanning adj electron adj microscope and secondary adj electron	USPAT; EPO; JPO; DERWENT	2004/07/08 15:55
-	513	(scanning adj electron adj microscope and secondary adj electron) and magnification	USPAT; EPO; JPO; DERWENT	2004/07/08 15:56
-	207	((scanning adj electron adj microscope and secondary adj electron) and magnification) and rate	USPAT; EPO; JPO; DERWENT	2004/07/08 15:56
-	53	((scanning adj electron adj microscope and secondary adj electron) and magnification) and rate near3 scan\$6	USPAT; EPO; JPO; DERWENT	2004/07/08 15:56
-	29	((((scanning adj electron adj microscope and secondary adj electron) and magnification) and rate) and sweep	USPAT; EPO; JPO; DERWENT	2004/07/08 15:56
-	31	((((scanning adj electron adj microscope and secondary adj electron) and magnification) and rate) and sweep\$5	USPAT; EPO; JPO; DERWENT	2004/07/08 15:56
-	13	((((scanning adj electron adj microscope and secondary adj electron) and magnification) and rate near3 scan\$6) and sweep\$5	USPAT; EPO; JPO; DERWENT	2004/07/09 08:52